

Search Notes**Application/Control No.**

10/652,496

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	517	1/27/2006	CN
715	520	1/27/2006	CN
715	507	1/27/2006	CN
715	505	1/27/2006	CN
715	908	1/27/2006	CN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	01/26/2006	CN
	1/27/2006	CN
	1/30/2006	CN
NPL Search on IEEE Database	1/30/2006	CN

INTERFERENCE SEARCHED

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